

DATA SHEET

FBL22031

9-bit BTL 3.3V latched/registered/pass-thru
Futurebus+ transceiver with 30 Ω
termination

Product specification
Supersedes data of 1998 Sep 04

2000 Apr 18

9-bit BTL 3.3V latched/registered/pass-thru Futurebus+ transceiver with 30Ω termination

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FEATURES

- Latched, registered or straight through in either A to B or B to A path
- Drives heavily loaded backplanes with equivalent load impedances down to 10Ω.
- High drive 100mA BTL open collector drivers on B-port
- Allows incident wave switching in heavily loaded backplane buses
- Reduced BTL voltage swing produces less noise and reduces power consumption
- Built-in precision band-gap reference provides accurate receiver thresholds and improved noise immunity
- Compatible with IEEE Futurebus+ or proprietary BTL backplanes
- Each BTL driver has a dedicated Bus GND for a signal return
- Controlled output ramp and multiple GND pins minimize ground bounce
- Glitch-free power up/power down operation
- Low I_{CC} current

- Tight output skew
- Supports live insertion
- Pins for the optional JTAG boundary scan function are provided
- High density packaging in plastic Quad Flatpack
- 5V compatible I/O on A-port
- Same pinout and function as the FBL2033 except for 30Ω series termination
- The A output includes a series resistor of 30Ω making external terminating resistors unnecessary

DESCRIPTION

The FBL22031 is a 9-bit latched/registered transceiver featuring a latched, registered or pass-thru mode in either the A-to-B or B-to-A direction.

The FBL22031 is designed with a 30Ω series resistor in both the HIGH and LOW states of the output.

The FBL22031 is intended to provide the electrical interface to a high performance wired-OR bus.

QUICK REFERENCE DATA

SYMBOL	PARAMETER		TYPICAL	UNIT
t_{PLH} t_{PHL}	Propagation delay An to $\overline{Bn}$		2.7	ns
t_{PLH} t_{PHL}	Propagation delay $\overline{Bn}$ to An		4.4 4.2	ns
C_O	Output capacitance ($\overline{B0} - \overline{Bn}$ only)		6	pF
I_{OL}	Output current ($\overline{B0} - \overline{Bn}$ only)		100	mA
I_{CC}	Supply current	AIn to $\overline{Bn}$ (outputs Low or High)	11	mA
		$\overline{Bn}$ to AOn (outputs Low)	22	
		$\overline{Bn}$ to AOn (outputs High)	18	

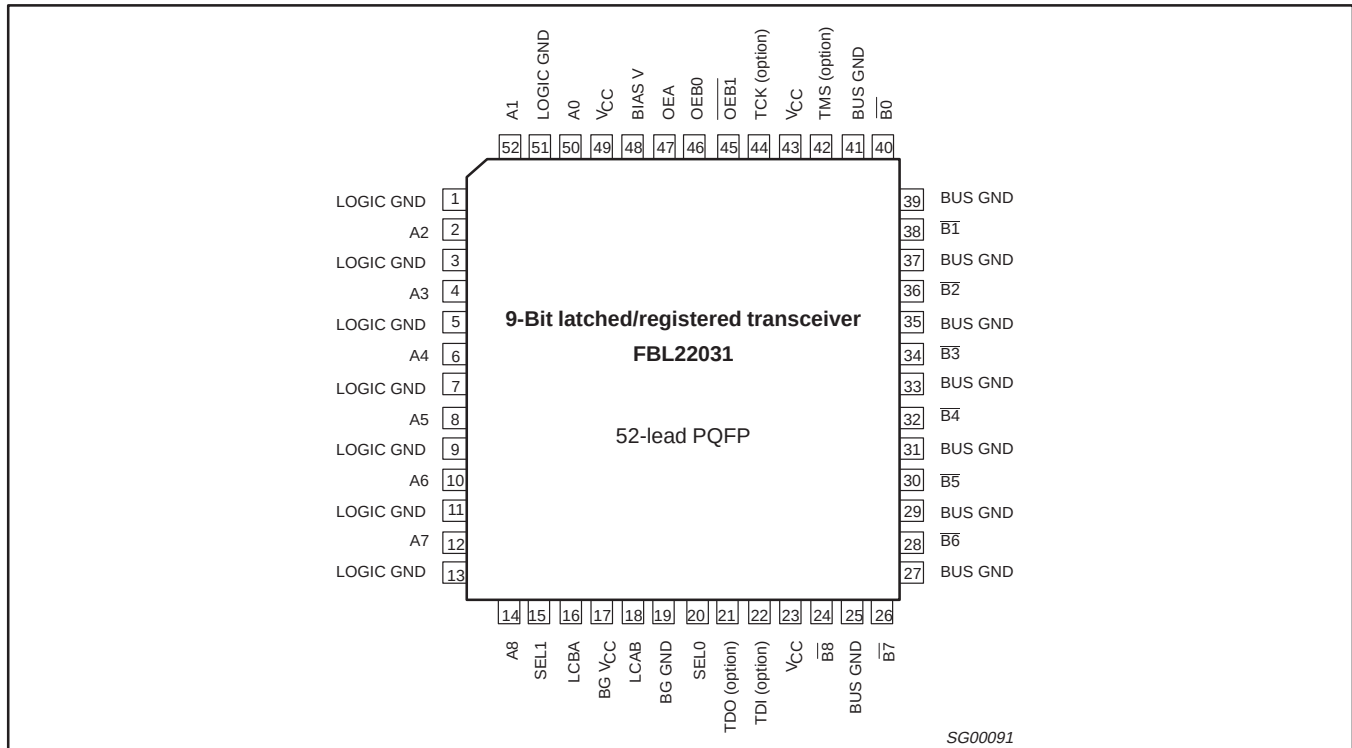
ORDERING INFORMATION

PACKAGE	$V_{CC} = 3.3V \pm 10\%$; $T_{amb} = -40^\circ C$ to $+85^\circ C$	DWG No.
52-pin Plastic Quad Flat Pack (PQFP)	FBL22031BB	SOT379-1

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PIN CONFIGURATION



PIN DESCRIPTION

SYMBOL	PIN NUMBER	TYPE	NAME AND FUNCTION
A0 – A8	50, 52, 2, 4, 6, 8, 10, 12, 14	I/O	BiCMOS data inputs/3-State outputs (TTL)
$\overline{B0} - \overline{B8}$	40, 38, 36, 34, 32, 30, 28, 26, 24	I/O	Data inputs/Open Collector outputs, High current drive (BTL)
OEBO	46	Input	Enables the B outputs when High
$\overline{OEB1}$	45	Input	Enables the B outputs when Low
OEA	47	Input	Enables the A outputs when High
BUS GND	25, 27, 29, 31, 33, 35, 37, 39, 41	GND	Bus ground (0V)
LOGIC GND	51, 1, 3, 5, 7, 9, 11, 13	GND	Logic ground (0V)
V _{CC}	23, 43, 49	Power	Positive supply voltage
BIAS V	48	Power	Live insertion pre-bias pin
BG V _{CC}	17	Power	Band Gap threshold voltage reference
BG GND	19	GND	Band Gap threshold voltage reference ground
SEL0	20	Input	Mode select
SEL1	15	Input	Mode select
LCAB	18	Input	A to B clock/latch enable (transparent latch when Low)
LCBA	16	Input	B to A clock/latch enable (transparent latch when Low)
TMS	42	Input	Test Mode Select (optional, if not implemented then no connect)
TCK	44	Input	Test Clock (optional, if not implemented then no connect)
TDI	22	Input	Test Data In (optional, if not implemented then no connect)
TDO	21	Output	Test Data Out (optional, if not implemented then shorted to TDI)

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DESCRIPTION

The TTL-level side (A port) has a common I/O. The common I/O, open collector B port operates at BTL signal levels. The logic element for data flow in each direction is controlled by two mode select inputs (SEL0 and SEL1). A "00" configures latches in both directions. A "10" configures thru mode in both directions. A "01" configures register mode in both directions. A "11" configures register mode in the A-to-B direction and latch mode in the B-to-A direction.

When configured in the buffer mode, the inverse of the input data appears at the output port. In the register mode, data is stored on the rising edge of the appropriate clock input (LCAB or LCBA). In the latch mode, clock pins serve as transparent-Low latch enables. Regardless of the mode, data is inverted from input to output.

The 3-State A port is enabled by asserting a High level on OEA. The B port has two output enables, OEB0 and $\overline{\text{OEB1}}$. Only when OEB0 is High and $\overline{\text{OEB1}}$ is Low is the output enabled.

When either OEB0 is Low or $\overline{\text{OEB1}}$ is High, the B port is inactive and is pulled to the level of the pull-up voltage. New data can be entered in the register and latched modes or can be retained while the associated outputs are in 3-State (A port) or inactive (B port).

The B-port drivers are Low-capacitance open collectors with controlled ramp and are designed to sink 100mA. Precision band gap references on the B-port insure very good noise margins by limiting the switching threshold to a narrow region centered at 1.55V.

The B-port interfaces to "Backplane Transceiver Logic" (see the IEEE 1194.1 BTL standard). BTL features low power consumption by reducing voltage swing (1V p-p, between 1V and 2V) and reduced capacitive loading by placing an internal series diode on the

drivers. BTL also provides incident wave switching, a necessity for high performance backplanes.

Output clamps are provided on the BTL outputs to further reduce switching noise. The " V_{OH} " clamp reduces inductive ringing effects during a Low-to-High transition. The " V_{OH} " clamp is always active. The other clamp, the "trapped reflection" clamp, clamps out ringing below the BTL 0.5V V_{OL} level. This clamp remains active for approximately 100ns after a High-to-Low transition.

To support live insertion, OEB0 is held Low during power on/off cycles to insure glitch-free B port drivers. Proper bias for B port drivers during live insertion is provided by the BIAS V pin when at a 3.3V level while V_{CC} is Low. The BIAS V pin is a low current input which will reverse-bias the BTL driver series Schottky diode, and also bias the B port output pins to a voltage between 1.62V and 2.1V. This bias function is in accordance with IEEE BTL Standard 1194.1. If live insertion is not a requirement, the BIAS V pin should be tied to a V_{CC} pin.

The LOGIC GND and BUS GND pins are isolated inside the package to minimize noise coupling between the BTL and TTL sides. These pins should be tied to a common ground external to the package.

Each BTL driver has an associated BUS GND pin that acts as a signal return path and these BUS GND pins are internally isolated from each other. In the event of a ground return fault, a "hard" signal failure occurs instead of a pattern dependent error that may be infrequent and impossible to troubleshoot.

As with any high power device, thermal considerations are critical. It is recommended that airflow (300lfpm) and/or thermal mounting be used to ensure proper junction temperature.

PACKAGE THERMAL CHARACTERISTICS

PARAMETER	CONDITION	52-PIN PLASTIC QFP
θ_{ja}	Still air	80°C/W
θ_{ja}	300 Linear feet per minute air flow	58°C/W
θ_{jc}	Thermally mounted on one side to heat sink	20°C/W

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FUNCTION TABLE

MODE	INPUTS									OUTPUTS	
	An	$\overline{\text{Bn}}^*$	OEB0	$\overline{\text{OEB1}}$	OEA	LCAB	LCBA	SEL0	SEL1	An	$\overline{\text{Bn}}$
An to $\overline{\text{Bn}}$ thru mode	L	—	H	L	L	X	X	H	L	input	H**
	H	—	H	L	L	X	X	H	L	input	L
An to $\overline{\text{Bn}}$ transparent latch	L	—	H	L	L	L	X	L	L	input	H**
	H	—	H	L	L	L	X	L	L	input	L
An to $\overline{\text{Bn}}$ latch and read	l	—	H	L	L	↑	X	L	L	input	H**
	h	—	H	L	L	↑	X	L	L	input	L
$\overline{\text{Bn}}$ outputs latched and read (preconditioned latch)	X	—	H	L	X	H	X	L	L	X	latched data
An to $\overline{\text{Bn}}$ register	l	—	H	L	L	↑	X	X	H	input	H**
	h	—	H	L	L	↑	X	X	H	input	L
$\overline{\text{Bn}}$ to An thru mode	—	L	Disable		H	X	X	H	L	H	input
	—	H	Disable		H	X	X	H	L	L	input
$\overline{\text{Bn}}$ to An transparent latch	—	L	Disable		H	X	L	L	L	H	input
	—	H	Disable		H	X	L	L	L	L	input
	—	L	Disable		H	X	L	H	H	H	input
	—	H	Disable		H	X	L	H	H	L	input
$\overline{\text{Bn}}$ to An latch and read	—	l	Disable		H	X	↑	L	L	H	input
	—	h	Disable		H	X	↑	L	L	L	input
	—	l	Disable		H	X	↑	H	H	H	input
	—	h	Disable		H	X	↑	H	H	L	input
An outputs latched and read (preconditioned latch)	—	X	X	X	H	X	H	L	L	latched data	X
	—	X	X	X	H	X	H	H	H	latched data	X
$\overline{\text{Bn}}$ to An register	—	l	Disable		H	X	↑	L	H	H	input
	—	h	Disable		H	X	↑	L	H	L	input
Disable $\overline{\text{Bn}}$ outputs	X	X	L	X	X	X	X	X	X	X	H**
	X	X	X	H	X	X	X	X	X	X	H**
Disable An outputs	X	X	X	X	L	X	X	X	X	Z	X

FUNCTION SELECT TABLE

MODE SELECTED	SEL0	SEL1
Thru mode	H	L
Register mode (An to Bn)	X	H
Latch mode (An to Bn)	L	L
Register mode (Bn to An)	L	H
Latch mode (Bn to An)	L	L
	H	H

NOTES:

H = High voltage level

L = Low voltage level

l = Low voltage level one set-up time prior to the Low-to-High LCXX transition

h = High voltage level one set-up time prior to the Low-to-High LCXX transition

X = Don't care

Z = High-impedance (OFF) state

— = Input not externally driven

↑ = Low-to-High transition

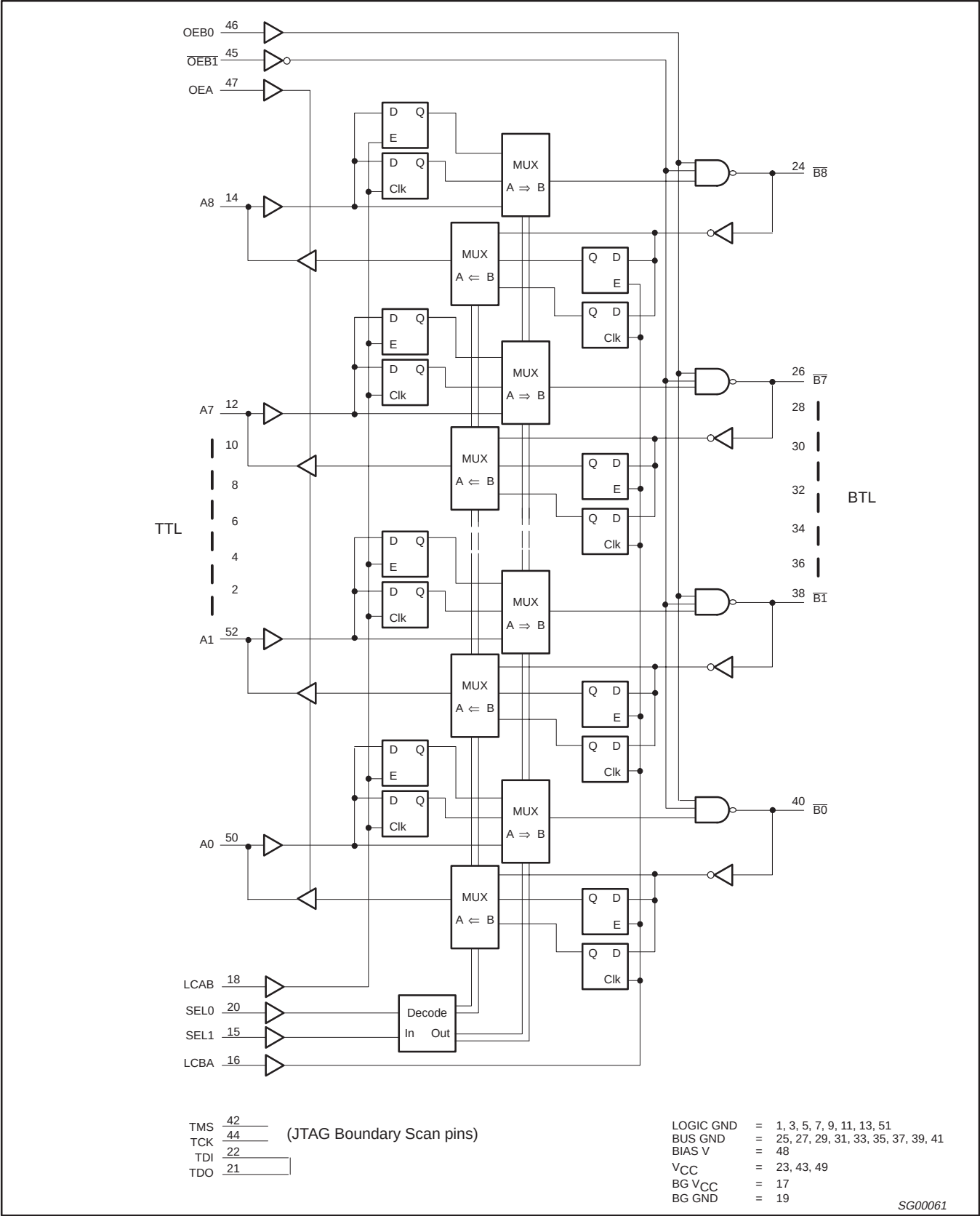
H** = Goes to level of pull-up voltage

 $\overline{\text{Bn}}^*$ = Precaution should be taken to ensure B inputs do not float. If they do, they are equal to Low state.Disable = OEB0 is Low or $\overline{\text{OEB1}}$ is High.

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LOGIC DIAGRAM



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ABSOLUTE MAXIMUM RATINGS

Operation beyond the limits set forth in this table may impair the useful life of the device.
Unless otherwise noted these limits are over the operating free-air temperature range.

SYMBOL	PARAMETER		RATING	UNIT
V _{CC}	Supply voltage		−0.5 to +4.6	V
V _{IN}	Input voltage	A10 – A16, OE _{B0} , OE _{Bn} , OE _{An}	−0.5 to +7.0	V
		$\overline{B0} - \overline{B8}$	−0.5 to +3.5	V
I _{IN}	Input current	V _{IN} < 0	−50	V
V _{OUT}	Voltage applied to output in High output state		−0.5 to +7.0	V
I _{OUT}	Current applied to output in Low output state/High output state	AO0 – AO8	24, −24	mA
		$\overline{B0} - \overline{B8}$	200	mA
T _{STG}	Storage temperature		−65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER		COMMERCIAL LIMITS V _{CC} = 3.3V±10%; T _{amb} = −40 to +85°C			UNIT
			MIN	TYP	MAX	
V _{CC}	Supply voltage		3.0	3.3	3.6	V
V _{IH}	High-level input voltage	Except $\overline{B0} - \overline{B8}$	2.0			V
		$\overline{B0} - \overline{B8}$	1.62	1.55		V
V _{IL}	Low-level input voltage	Except $\overline{B0} - \overline{B8}$			0.8	V
		$\overline{B0} - \overline{B8}$			1.47	V
I _{IK}	Input clamp current				−18	mA
I _{OH}	High-level output current	AO0 – AO8			−12	mA
I _{OL}	Low-level output current	AO0 – AO8			+12	mA
		$\overline{B0} - \overline{B8}$			100	mA
C _{OB}	Output capacitance on B port			6	7	pF
T _{amb}	Operating free-air temperature range		0		+70	°C

LIVE INSERTION SPECIFICATIONS

SYMBOL	PARAMETER		LIMITS			UNIT
			MIN	TYP	MAX	
V _{BIASV}	Bias pin voltage	Voltage difference between the Bias voltage and V _{CC} after the PCB is plugged in.	–	–	0.5	V
I _{BIASV}	Bias pin (I _{BIASV}) input DC current	V _{CC} = 0 V, Bias V = 3.6V			1.2	mA
		V _{CC} = 3.3V, Bias V = 3.6V			10	μA
V _{Bn}	Bus voltage during prebias	$\overline{B0} - \overline{B8} = 0V$, Bias V = 3.3V	1.62		2.1	V
I _{LM}	Fall current during prebias	$\overline{B0} - \overline{B8} = 2V$, Bias V = 1.3 to 2.5V			1	μA
I _{HM}	Rise current during prebias	$\overline{B0} - \overline{B8} = 1V$, Bias V = 3 to 3.6V	−1			μA
I _{BnPEAK}	Peak bus current during insertion	V _{CC} = 0 to 3.3V, $\overline{B0} - \overline{B8} = 0$ to 2.0V, Bias V = 2.7 to 3.6V, OE _{B0} = 0.8V, t _r = 2ns			10	mA
I _{OLOFF}	Power up current	V _{CC} = 0 to 3.3V, OE _{B0} = 0.8V			100	μA
		V _{CC} = 0 to 1.2V, OE _{B0} = 0 to 5V			100	
t _{GR}	Input glitch rejection		1.0	1.35		ns

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DC ELECTRICAL CHARACTERISTICS

Over recommended operating free-air temperature range unless otherwise noted.

SYMBOL	PARAMETER		TEST CONDITIONS ¹	LIMITS			UNIT
				MIN	TYP ²	MAX	
I_{OH}	High level output current	$\overline{B0} - \overline{B8}$	$V_{CC} = \text{MAX}, V_{IL} = \text{MAX}, V_{OH} = 1.9\text{V}$			100	μA
I_{OFF}	Power-off output current	$\overline{B0} - \overline{B8}$	$V_{CC} = 0\text{V}, V_{IL} = \text{MAX}, V_{OH} = 1.9\text{V}$			100	μA
			$V_{CC} = 0\text{V}, V_{IL} = \text{MAX}, V_{OH} = 1.9\text{V} @ 85^\circ\text{C}$			300	μA
V_{OH}	High-level output voltage	AO0 – AO8 ³	$V_{CC} = \text{MIN to MAX}, I_{OH} = -100\mu\text{A}$	$V_{CC}-0.2$			V
			$V_{CC} = \text{MIN}; I_{OH} = -4\text{mA}$	2.4			V
			$V_{CC} = \text{MIN}; I_{OH} = -12\text{mA}$	2.0			V
V_{OL}	Low-level output voltage	AO0 – AO8 ³	$V_{CC} = \text{MIN}; I_{OL} = 4\text{mA}$			0.4	V
			$V_{CC} = \text{MIN}; I_{OL} = 12\text{mA}$			0.8	V
		$\overline{B0} - \overline{B8}$	$V_{CC} = \text{MIN}, I_{OL} = 4\text{mA}$	0.5			V
			$V_{CC} = \text{MIN}, I_{OL} = 100\text{mA}$	0.75	1.0	1.20	V
V_{IK}	Input clamp voltage		$V_{CC} = \text{MIN}, I_I = I_{IK} = -18\text{mA}$		-0.85	-1.2	V
I_I	Input leakage current	Control pins	$V_{CC} = 3.6\text{V}; V_I = V_{CC} \text{ or } 100\text{mV}$			± 1.0	μA
		Control/AI0 – AI8	$V_{CC} = 0\text{V or } 3.6\text{V}; V_I = 5.5\text{V}$			10	μA
		AI0 – AI8	$V_{CC} = 3.6\text{V}; V_I = V_{CC}$			1	μA
		Note 4	$V_{CC} = 3.6\text{V}; V_I = 100\text{mV}$			-5	μA
I_{IH}	High-level input current	$\overline{B0} - \overline{B8}$	$V_{CC} = \text{MAX}, V_I = 1.9\text{V}$			100	μA
			$V_{CC} = \text{MAX}, V_I = 3.5\text{V}, \text{note } 5$	100			mA
			$V_{CC} = \text{MAX}, V_I = 3.75\text{V}, \text{note } 5 @ -40^\circ\text{C}$	100			mA
I_{IL}	Low-level input current	$\overline{B0} - \overline{B8}$	$V_{CC} = \text{MAX}, V_I = 0.75\text{V}$			-100	μA
I_{OZH}	Off-state output current	AO0 – AO8	$V_{CC} = \text{MAX}, V_O = 3\text{V}$			5	μA
I_{OZL}	Off-state output current	AO0 – AO8	$V_{CC} = \text{MAX}, V_O = 0.5\text{V}$			-5	μA
I_{CC}	Supply current (total)	$I_{CCH} \text{ B to A}$	$V_{CC} = \text{MAX}, \text{outputs High}$		18	32	mA
		$I_{CCL} \text{ B to A}$	$V_{CC} = \text{MAX}, \text{outputs Low}$		22	37	mA
		$I_{CCH} \text{ A to B}$	$V_{CC} = \text{MAX}, \text{outputs High}$		11	16	mA
		$I_{CCL} \text{ A to B}$	$V_{CC} = \text{MAX}, \text{outputs Low}$		11	16	mA
		I_{CCZ}	$V_{CC} = \text{MAX}$		18	32	mA

NOTES:

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operation conditions for the applicable type.
- All typical values are at $V_{CC} = 3.3\text{V}$, $T_A = 25^\circ\text{C}$.
- Due to test equipment limitations, actual test conditions are $V_{IH} = 1.8\text{V}$ and $V_{IL} = 1.3\text{V}$ for the B side.
- Unused pins are at V_{CC} or GND.
- For B port input voltage between 3 and 5 volt; I_{IH} will be greater than 100mA but the part will continue to function normally (clamping circuit is active).

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AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	B TO A SPECIFICATIONS					UNIT
			T _{amb} = +25°C, V _{CC} = 3.3V,			T _{amb} = −40 to +85°C, V _{CC} = 3.3V±10%,		
			MIN	TYP	MAX	MIN	MAX	
f _{MAX}	Maximum clock frequency	Waveform 4	120	150				MHz
t _{PLH} t _{PHL}	Propagation delay (thru mode) Bn to An	Waveform 1, 2	2.3 2.6	5.4 5.6	8.9 9.1	1.7 2.1	10.1 10.3	ns
t _{PLH} t _{PHL}	Propagation delay (transparent latch) Bn to An	Waveform 1, 2	3.2 3.5	6.5 6.3	10.1 9.3	2.4 2.9	11.6 10.3	ns
t _{PLH} t _{PHL}	Propagation delay LCBA to An (latch)	Waveform 1, 2	6.8 5.5	10.4 9.8	14.4 14.7	5.1 4.3	16.9 16.8	ns
t _{PLH} t _{PHL}	Propagation delay LCBA to An (register)	Waveform 1, 2	2.1 2.3	4.9 5.2	8.4 8.3	1.2 1.8	9.7 9.4	ns
t _{PLH} t _{PHL}	Propagation delay SEL0 or SEL1 to An (inverting)	Waveform 1, 2	2.7 2.5	6.5 6.3	10.7 10.5	1.8 2.0	12.8 11.8	ns
t _{PLH} t _{PHL}	Propagation delay SEL0 or SEL1 to An (non-inverting)	Waveform 1, 2	2.4 2.6	6.6 6.2	11.3 10.2	1.8 2.1	13.0 11.6	ns
t _{PZH} t _{PHZ}	Output enable time from High or Low OEA to An	Waveform 5, 6	2.6 3.4	5.8 5.4	9.3 7.5	1.9 2.9	10.7 9.0	ns
t _{PZL} t _{PLZ}	Output disable time to High or Low OEA to An	Waveform 5, 6	2.1 1.2	5.4 3.1	9.1 5.4	1.6 1.0	10.1 6.0	ns
t _{TLH} t _{THL}	Output transition time, An Port 10% to 90%, 90% to 10%	Test Circuit and Waveforms				0.7 0.5	3.0 2.0	ns
t _{SK} (o)	Output to output skew for multiple channels ¹	Waveform 3		0.5	1.0		1.5	ns
t _{SK} (p)	Pulse skew ² t _{PHL} − t _{PLH} _{MAX}	Waveform 2		0.5	1.0		1.5	ns

NOTES:

- $|t_{PNactual} - t_{PMactual}|$ for any data input to output path compared to any other data input to output path where N and M are either LH or HL. Skew times are valid only under same test conditions (temperature, V_{CC} , loading, etc.). $t_{SK(O)}$ compares t_{PLH} on a given path to t_{PLH} on any other path or compares t_{PHL} on a given path to t_{PHL} on any other path.
- $t_{SK(P)}$ is used to quantify duty cycle characteristics. In essence it compares the input signal duty cycle to the corresponding output signal duty cycle (50MHz input frequency and 50% duty cycle, tested on data paths only).

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AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	A TO B 9 Ω LOAD SPECIFICATIONS						UNIT
			T _{amb} = +25°C, V _{CC} = 3.3V,			T _{amb} = −40 to +85°C, V _{CC} = 3.3V±10%,			
			MIN	TYP	MAX	MIN	MAX		
t _{PLH} t _{PHL}	Propagation delay (thru latch) An to Bn	Waveform 1, 2	1.2 1.2	3.5 3.1	8.1 6.5	1.0 1.0	9.1 6.9	ns	
t _{PLH} t _{PHL}	Propagation delay (transparent latch) An to Bn	Waveform 1, 2	1.2 1.3	3.8 4.0	8.6 7.7	1.0 1.0	9.5 8.4	ns	
t _{PLH} t _{PHL}	Propagation delay LCAB to Bn (latch)	Waveform 1, 2	7.2 7.2	12.0 11.1	17.4 15.5	5.3 5.6	20.5 17.8	ns	
t _{PLH} t _{PHL}	Propagation delay LCAB to Bn (register)	Waveform 1, 2	1.2 1.4	4.4 4.3	8.8 7.5	1.0 1.0	10.2 8.4	ns	
t _{PLH} t _{PHL}	Propagation delay SEL0 or SEL1 to Bn (inverting)	Waveform 1, 2	1.2 1.6	5.1 4.6	9.8 8.1	1.0 1.1	11.4 9.9	ns	
t _{PLH} t _{PHL}	Propagation delay SEL0 or SEL1 to Bn (non-inverting)	Waveform 1, 2	1.9 1.9	5.6 4.7	9.9 7.9	1.0 1.3	11.2 9.0	ns	
t _{PLH} t _{PHL}	OEBn to Bn	Waveform 1, 2	1.2 1.2	4.0 3.7	8.4 6.7	1.0 1.0	9.8 8.0	ns	
t _{TLH} t _{THL}	Output transition time, $\overline{\text{Bn}}$ Port (1.3V to 1.8V)	Test Circuit and Waveforms				1.2 0.4	3.0 1.5	ns	
t _{sk(o)}	Output to output skew for multiple channels ¹	Waveform 3		0.4	1.0		2.0	ns	
t _{sk(p)}	Pulse skew ² $ t_{\text{PHL}} - t_{\text{PLH}} _{\text{MAX}}$	Waveform 2		0.3	1.0		1.5	ns	

NOTES:

- $|t_{PNactual} - t_{PMactual}|$ for any data input to output path compared to any other data input to output path where N and M are either LH or HL. Skew times are valid only under same test conditions (temperature, V_{CC} , loading, etc.). $t_{SK(0)}$ compares t_{PLH} on a given path to t_{PLH} on any other path or compares t_{PHL} on a given path to t_{PHL} on any other path.
- $t_{SK(p)}$ is used to quantify duty cycle characteristics. In essence it compares the input signal duty cycle to the corresponding output signal duty cycle (50MHz input frequency and 50% duty cycle, tested on data paths only).

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AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	A TO B 16.5 Ω LOAD SPECIFICATIONS						UNIT
			T _{amb} = +25°C, V _{CC} = 3.3V,			T _{amb} = −40 to +85°C, V _{CC} = 3.3V±10%,			
			MIN	TYP	MAX	MIN	MAX		
t _{PLH} t _{PHL}	Propagation delay (thru latch) An to Bn	Waveform 1, 2	1.2 1.3	4.1 3.5	7.4 5.9	1.0 1.1	8.7 6.4	ns	
t _{PLH} t _{PHL}	Propagation delay (transparent latch) An to Bn	Waveform 1, 2	1.2 1.6	4.3 4.3	8.0 7.3	1.0 1.2	9.3 8.1	ns	
t _{PLH} t _{PHL}	Propagation delay LCAB to Bn (latch)	Waveform 1, 2	6.6 6.7	11.8 10.9	17.6 15.7	4.8 5.2	20.6 18.1	ns	
t _{PLH} t _{PHL}	Propagation delay LCAB to Bn (register)	Waveform 1, 2	1.2 1.2	4.3 4.1	8.8 7.6	1.0 1.0	10.1 8.5	ns	
t _{PLH} t _{PHL}	Propagation delay SEL0 or SEL1 to Bn (inverting)	Waveform 1, 2	1.3 1.7	5.3 4.9	9.7 8.6	1.0 1.3	11.2 9.6	ns	
t _{PLH} t _{PHL}	Propagation delay SEL0 or SEL1 to Bn (non-inverting)	Waveform 1, 2	1.8 1.8	5.6 4.7	9.8 7.9	1.0 1.1	11.3 9.0	ns	
t _{PLH} t _{PHL}	OEBn to Bn	Waveform 1, 2	1.3 1.7	4.4 4.0	8.1 6.7	1.0 1.0	9.4 7.8	ns	
t _{TLH} t _{THL}	Output transition time, $\overline{\text{Bn}}$ Port (1.3V to 1.8V)	Test Circuit and Waveforms				1.2 0.4	3.0 1.5	ns	
t _{sk(o)}	Output to output skew for multiple channels ¹	Waveform 3		0.4	1.0		2.0	ns	
t _{sk(p)}	Pulse skew ² $ t_{\text{PHL}} - t_{\text{PLH}} _{\text{MAX}}$	Waveform 2		0.3	1.0		1.5	ns	

NOTES:

- $|t_{PNactual} - t_{PMactual}|$ for any data input to output path compared to any other data input to output path where N and M are either LH or HL. Skew times are valid only under same test conditions (temperature, V_{CC} , loading, etc.). $t_{SK(0)}$ compares t_{PLH} on a given path to t_{PLH} on any other path or compares t_{PHL} on a given path to t_{PHL} on any other path.
- $t_{SK(p)}$ is used to quantify duty cycle characteristics. In essence it compares the input signal duty cycle to the corresponding output signal duty cycle (50MHz input frequency and 50% duty cycle, tested on data paths only).

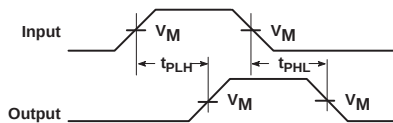
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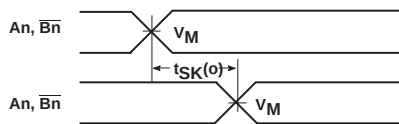
AC SETUP REQUIREMENTS (Commercial)

SYMBOL	PARAMETER	TEST CONDITION	LIMITS			UNIT
			$T_{amb} = +25^{\circ}\text{C}$, $V_{CC} = 3.3\text{V}$,		$T_{amb} = -40 \text{ to } +85^{\circ}\text{C}$, $V_{CC} = 3.3\text{V}\pm 10\%$,	
			$C_L = 50\text{pF}$ (A side) / $C_D = 30\text{pF}$ (B side) $R_L = 500\Omega$ (A side) / $R_U = 16.5\Omega$ (B side)			
			MIN	TYP	MIN	
$t_s(\text{H})$ $t_s(\text{L})$	Setup time An to LCAB	Waveform 4	1.3 1.3		1.5 1.5	ns
$t_h(\text{H})$ $t_h(\text{L})$	Hold time An to LCAB	Waveform 4	1.0 1.0		1.0 1.0	ns
$t_s(\text{H})$ $t_s(\text{L})$	Setup time Bn to LCBA	Waveform 4	5.0 4.0		6.0 4.5	ns
$t_h(\text{H})$ $t_h(\text{L})$	Hold time Bn to LCBA	Waveform 4	0.0 0.0		0.0 0.0	ns
$t_w(\text{H})$ $t_w(\text{L})$	Pulse width, High or Low LCAB or LCBA	Waveform 4	3.0 3.0		3.0 3.0	ns

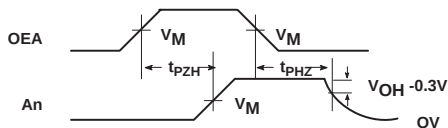
AC WAVEFORMS



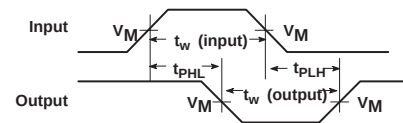
Waveform 1. Propagation Delay for Data or Output Enable to Output



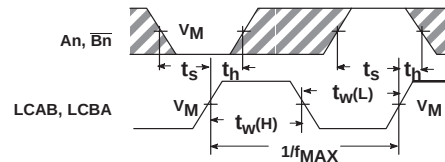
Waveform 3. Output to Output Skew



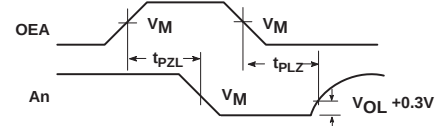
Waveform 5. 3-State Output Enable Time to High Level and Output Disable Time from High Level



Waveform 2. Propagation Delay for Data or Output Enable to Output



Waveform 4. Setup and Hold Times, Pulse Widths and Maximum Frequency



Waveform 6. 3-State Output Enable Time to Low Level and Output Disable Time from Low Level

NOTE: $V_M = 1.55\text{V}$ for $\overline{\text{Bn}}$, $V_M = 1.5\text{V}$ for all others.

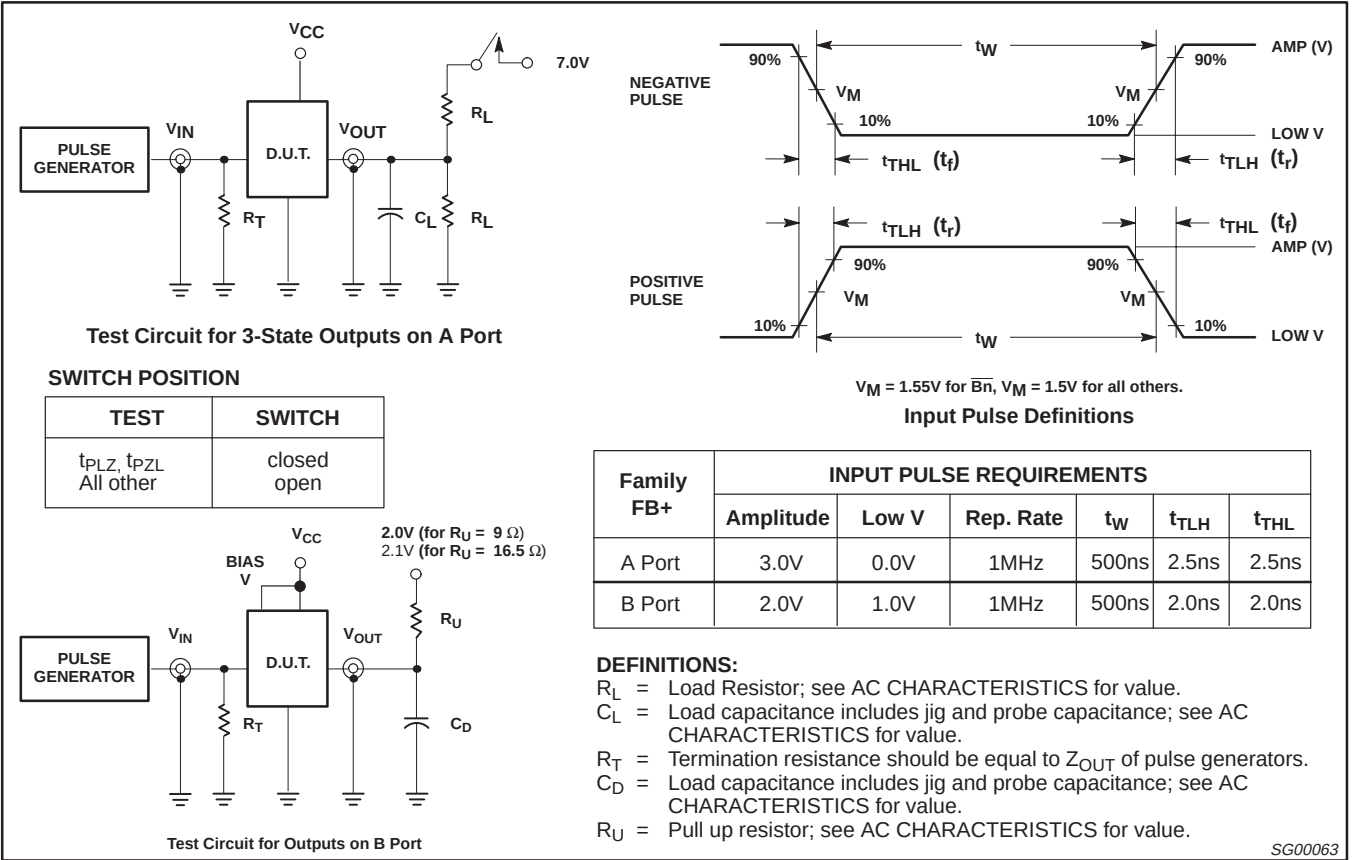
The shaded areas indicate when the input is permitted to change for predictable output performance.

SG00062

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TEST CIRCUIT AND WAVEFORMS

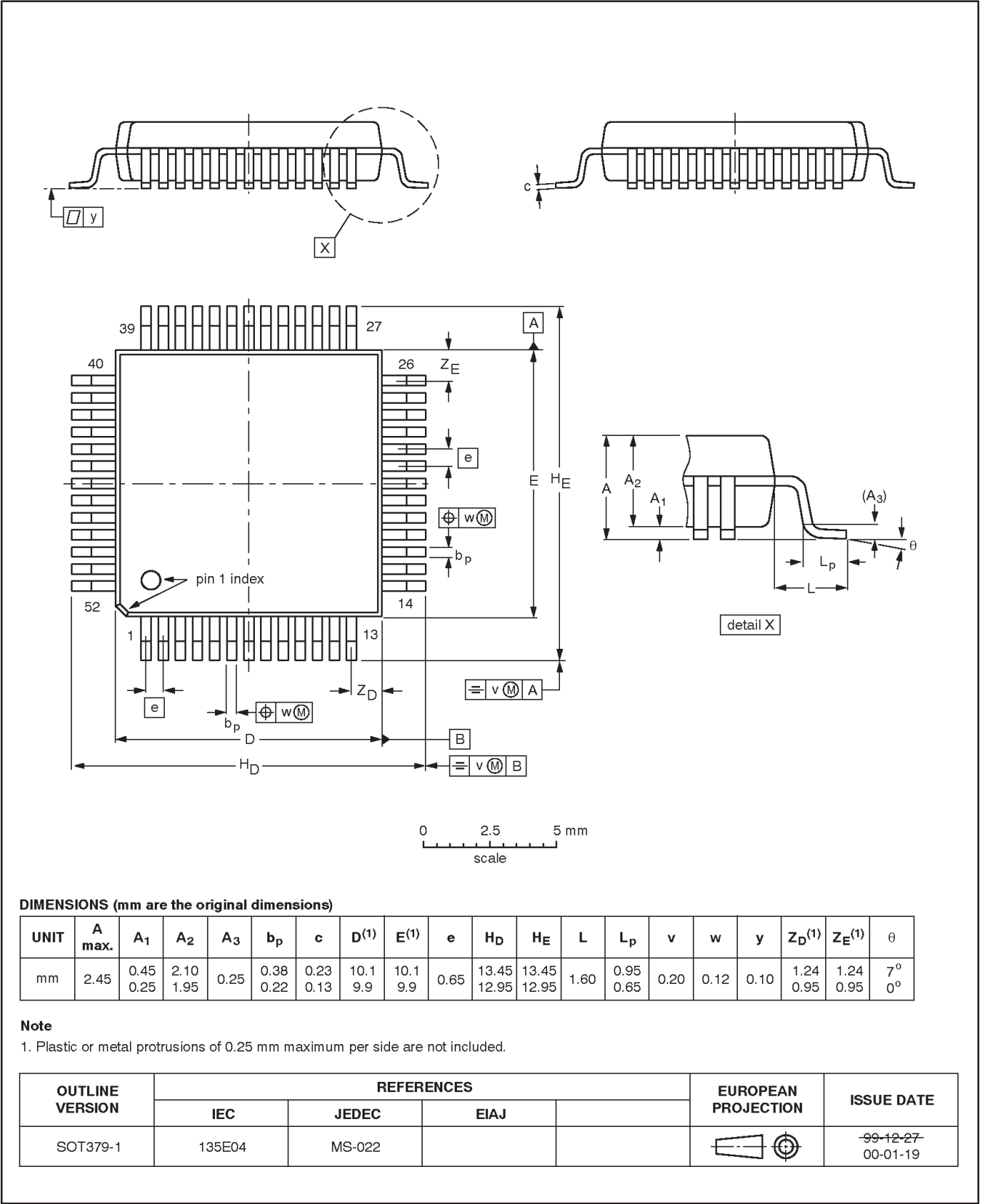


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QFP52: plastic quad flat package; 52 leads (lead length 1.6 mm); body 10 x 10 x 2.0 mm

SOT379-1



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NOTES

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Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
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[1] Please consult the most recently issued datasheet before initiating or completing a design.

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